

FAST - PROC - 067

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE

Richard J Schnurr

Rick Schnurr 745.2

Timothy D Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure.	Verify_____
Set up ESD station in Mag Cal Facility.	Verify_____
Place printed wiring board on measurement stand.	Verify_____
Measure Magnetic properties of Card.	Verify_____
Degauss Card.	Verify_____
Measure Magnetic properties of Card.	Verify_____
Apply a ^{Three} one gauss feild to the card.	Verify_____
Measure Magnetic properties of Card.	Verify_____
Degauss Card.	Verify_____
Measure Magnetic properties of Card.	Verify_____
Repack Card in ESD container.	Verify_____

FAST - PROC - 067

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE

Flrsh+ BCC

Richard J. Schnurr

Rick Schnurr 745.2

Timothy D. Gruner

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Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

MUE Flasher BCC Battery charge control

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure.	Verify <u>R6J</u>	
Set up ESD station in Mag Cal Facility.	Verify <u>R6J</u>	
Place printed wiring board on measurement stand.	Verify <u>R6J</u>	→ Remove connector. R6J
Measure Magnetic properties of Card.	Verify <u>R6J</u>	
Degauss Card. 30 gauss	Verify <u>R6J</u>	
Measure Magnetic properties of Card.	Verify <u>R6J</u>	
Apply a ^{Three} one gauss field to the card. in X direction	Verify <u>R6J</u>	
Measure Magnetic properties of Card.	Verify <u>R6J</u>	
Degauss Card. 30 gauss	Verify <u>R6J</u>	
Measure Magnetic properties of Card.	Verify <u>_____</u>	skipped
Repack Card in ESD container.	Verify <u>R6J</u>	

Top of Box North (X)
card up

FAST MUE BCC

BCC/1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
INITIAL PERMDISTANCE (M)
PROBE 1= 1 : PROBE 2= 1.25 : PROBE 3= 1.5

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	-.3	-.5	-.2	-.3	-.3	-.0	.1	-.3	.2
10	0.0	-.5	-.3	.1	.1	.1	-.1	-.4	.2
20	-.5	-.1	-.4	-.4	-.5	-.0	-.1	-.3	.1
30	-.3	-.3	-.4	.2	-.2	.1	-.1	-.3	.2
40	-.2	-.6	-.3	-.3	-.3	.1	-.1	0.0	.2
50	-.4	.1	-.3	.1	-.4	-.1	-.1	0.0	.1
60	0.0	-.5	-.3	.4	-.2	.0	-.1	-.1	.2
70	-.6	-.3	-.1	.1	-.4	.3	-.3	-.2	.2
80	.1	.1	-.3	.3	.1	.1	-.1	-.2	.1
90	-.2	-.3	-.4	.1	-.1	.0	-.1	-.2	.1
100	-.4	-.5	-.3	-.1	-.3	-.0	-.1	-.2	.1
110	-.2	-.5	-.4	.2	-.3	-.0	-.2	-.1	.1
120	-.2	-.6	-.4	-.1	-.4	.0	-.2	-.1	.1
130	-.2	-.4	-.4	.2	-.3	.0	-.2	-.2	.1
140	.1	-.5	-.3	-.2	-.3	.0	-.1	-.2	.1
150	0.0	-.4	-.4	.5	-.2	-.0	-.1	-.2	.1
160	-.1	-.4	-.3	.2	-.4	.0	.1	-.3	.1
170	-.1	-.4	-.3	.4	-.3	.1	-.1	-.2	.2
180	0.0	-.3	-.4	.3	-.2	-.1	-.2	0.0	.1
190	-.2	-.5	-.3	.5	-.4	-.1	-.1	-.1	.1
200	.1	-.6	-.5	.4	-.5	-.1	-.1	-.1	.1
210	.2	-.5	-.4	.6	-.4	.1	.1	-.1	.1
220	0.0	.2	-.3	.4	.3	.1	.1	-.2	.1
230	.1	-.4	-.3	.5	-.3	.0	.1	-.2	.2
240	-.2	-.2	-.3	-.1	-.4	.0	.1	-.1	.1
250	-.3	-.4	-.3	-.1	-.3	-.0	-.2	0.0	.1
260	-.5	-.4	-.2	-.3	-.3	.0	-.1	-.2	.2
270	-.2	-.4	-.4	.1	-.2	.1	-.3	-.1	.2
280	-.5	-.2	-.3	.1	-.2	-.0	.1	-.1	.3
290	-.4	-.1	-.2	.1	-.2	.0	-.1	-.2	-.1
300	-.4	-.1	-.1	-.1	.2	.1	-.2	-.2	.2
310	-.3	-.3	-.2	.1	-.2	-.1	-.1	-.1	.1
320	.1	-.8	-.4	.4	.1	.0	-.2	-.2	.2
330	0.0	.1	-.2	-.1	-.5	-.1	-.1	-.1	-.0
340	-.3	-.3	-.1	-.2	-.4	.1	.1	-.3	.2
350	.2	-.4	-.2	.4	-.5	.0	-.1	-.1	.1

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
-.5	-.0	9.5	9.5

FAST MUE BCC

BCC/3 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	.6	.1	-5.2	-.8	.1	-.9	-.7	.1	.0
10	-.2	.2	-5.0	-.5	.3	-.2	-.3	.1	-.2
20	.3	-.3	-5.4	-.6	-.4	-.9	-.6	.1	-.2
30	-.3	-.1	-5.3	-.6	.7	-1.4	-.8	0.0	-.1
40	-.4	-.2	-5.6	-.2	.2	-.7	-.4	-.1	.0
50	-.7	.2	-5.5	-.8	-.2	-.8	-.6	-.1	-.3
60	.6	.3	-5.9	-.2	-.4	-1.4	-.6	.1	-.3
70	.2	0.0	-5.6	.2	.1	-.8	-.6	.1	-.1
80	.3	-.4	-7.5	-.6	.1	-1.0	-.6	0.0	-.2
90	.1	-.2	-7.1	-.7	0.0	-1.2	-.7	-.1	-.1
100	.6	0.0	-7.3	-.3	-.6	-1.0	-.9	-.3	-.1
110	-.6	.1	-7.0	-.9	-.1	-.4	-.7	-.1	-.3
120	-.2	-.2	-8.0	-.7	-.4	-1.0	-.8	0.0	-.0
130	-.2	-.1	-5.6	-.2	-.5	-.8	-.6	-.2	.0
140	-1.2	-.4	-7.7	-.9	.3	-1.1	-.6	-.2	-.2
150	-.9	-.1	-7.1	-.7	.2	-1.6	-.6	-.1	-.3
160	-.4	-1.0	-5.9	.1	-.2	-.5	-.6	0.0	-.4
170	-.3	-.6	-6.0	-.4	-.3	-.5	-.7	.1	-.2
180	.6	-.9	-5.1	-.3	-.3	-.4	-.6	-.2	-.2
190	.7	-.7	-5.8	-.3	-.3	-.1	-.6	0.0	-.4
200	1.0	-.9	-4.4	-.2	-.2	-.8	-.6	-.2	-.0
210	-.1	-.6	-4.0	-1.1	0.0	-1.2	-.3	-.2	-.3
220	.9	-1.3	-4.0	-.3	-.3	-.4	-.4	-.3	-.2
230	1.7	-.5	-3.3	.5	-.4	-.4	-.6	-.1	-.2
240	.4	-.1	-3.7	-.4	.2	-.3	-.3	-.4	-.0
250	1.7	-.4	-3.3	.3	-.5	-.2	-.5	-.2	-.1
260	1.2	-.3	-3.9	.4	.1	-.1	-.7	-.5	-.2
270	1.4	-.1	-3.1	.1	-.4	-.1	-.5	-.4	-.2
280	.3	1.1	-3.6	-.9	.2	-.4	-.5	-.3	-.1
290	1.1	-.5	-3.8	.3	-.4	-.1	-.6	-.4	-.2
300	1.7	.4	-1.9	.5	-.4	-.5	-.5	-.1	-.2
310	.9	0.0	-2.4	.6	-.3	-.7	-.6	-.2	-.2
320	-.1	0.0	-3.5	-.3	.5	-1.3	-.7	0.0	-.1
330	-.3	-.1	-4.5	-.2	.4	-1.2	-.5	-.1	-.3
340	-.6	.5	-4.7	-1.5	.1	-.9	-.5	-.1	-.1
350	.2	-.1	-3.2	-.3	-.4	-.8	-.7	.1	-.2

DIPOLE MOMENTS IN GAUSS-CM³

X	Y	Z	T
-.0	-.4	6.2	6.2

FAST MUE BCC

BCC/2 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION

DISTANCE (M)

POST 3G EXPOSURE

PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	1.4	-.3	-5.5	-.4	-.1	-.7	.5	-.3	-.3
10	.7	.4	-5.6	.4	-.3	-.3	.3	-.2	-.2
20	1.1	.3	-4.6	0.0	.1	-.7	.3	-.2	-.4
30	.5	.2	-4.3	-.1	.1	-.3	.2	-.3	-.3
40	.5	.4	-5.6	-.3	-.2	-1.6	.3	-.2	-.2
50	.9	.3	-5.8	-.6	0.0	-1.1	.2	-.1	-.1
60	.9	0.0	-6.1	1.1	0.0	-.7	.5	-.1	-.0
70	1.1	.4	-7.0	0.0	-.2	-.9	-.1	0.0	-.2
80	.6	-.1	-7.6	-.4	.2	-.6	.1	-.1	-.3
90	1.1	-.3	-7.9	1.3	-.1	-.5	.4	.2	-.2
100	1.4	.4	-8.8	.3	-.2	-.8	.2	.2	-.2
110	-.4	.2	-8.4	-.1	.2	-.3	.3	.1	-.1
120	-.8	.3	-9.1	-.8	.4	-.6	.5	-.2	-.3
130	.4	-.7	-8.0	.8	-.6	-1.1	.3	-.1	-.1
140	.7	-.4	-7.4	-.1	-.2	-.6	-.5	-.1	-.1
150	-.5	.1	-7.1	-.9	-.5	-.4	.2	-.1	-.1
160	-.9	-1.0	-6.9	-.6	-.3	-.6	-.3	-.1	-.2
170	-.2	-1.0	-6.6	-.9	-.7	-.9	-.6	0.0	-.2
180	-.5	-.9	-6.8	-1.4	-.1	-.3	-.6	-.2	-.0
190	.9	-.7	-6.6	-.2	-.4	-.4	-.3	-.2	-.1
200	.5	-.7	-4.6	-.5	-.5	-.2	-.2	-.3	-.0
210	.5	-.9	-5.9	-.5	-.5	-.5	-.3	-.2	-.2
220	1.1	-.8	-4.5	-.6	-.4	-.1	-.3	-.3	-.1
230	.6	-.7	-4.8	.1	-.5	-.9	-.3	.1	-.1
240	1.2	-.7	-4.6	-.5	-.6	-.3	-.4	-.1	-.1
250	.8	-.5	-4.8	.2	-.6	-.2	-.4	-.1	-.2
260	1.3	-.9	-3.7	-.2	-.2	-.4	-.5	0.0	0.0
270	.5	-.2	-4.3	-.3	-.3	-.2	-.2	.1	-.1
280	0.0	-.3	-4.0	-.5	-.1	-.6	-.2	0.0	-.0
290	.8	-.6	-4.6	-.6	-.9	.1	-.1	0.0	-.2
300	1.0	-.7	-3.8	.3	-.5	-.2	-.3	0.0	-.1
310	1.4	-.7	-3.8	.3	-.9	-.1	-.2	-.1	-.2
320	.5	0.0	-4.1	-.9	-.2	-.7	-.3	-.1	-.1
330	-.4	-.4	-5.0	-.9	.4	-1.2	-.4	-.2	-.1
340	.5	.3	-4.5	-.8	-.3	-.5	-.2	0.0	-.2
350	.6	.6	-5.4	-.2	.4	-.6	-.4	0.0	-.1

DIPOLE MOMENTS IN GAUSS-CM³

X	Y	Z	T
.2	-.1	7.4	7.4

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE

End plate with shield.

Richard J Schnurr

Rick Schnurr 745.2

Timothy D Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

FAST MUE END PLATE W/SHIELD END/3.1 DATE:12/13/93

NETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERM

DISTANCE (M)
PROBE 1= .5 ; PROBE 2= .75 ; PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	.4	-7.1	-1.1	-2.3	-.6	-.9	-.9	-.1	.7
10	2.3	-3.6	-.2	-1.7	-.4	-.3	-.8	-.2	-.1
20	1.6	-.1	-.8	-1.5	.2	-2.0	-.7	0.0	.1
30	-1.4	4.7	-.4	-2.2	.9	-1.6	-.8	0.0	.1
40	-5.7	6.4	-1.6	-2.6	.8	-1.7	-1.1	.1	.8
50	-10.7	7.6	-1.6	-3.3	1.2	-.9	-1.2	.2	.5
60	-16.4	7.0	-2.2	-4.1	.5	-2.3	-1.3	-.2	.3
70	-21.0	4.2	-3.2	-4.6	-.6	-1.3	-1.3	-.5	-.3
80	-23.2	-.1	-2.5	-5.2	-1.4	-2.5	-1.3	-.7	.4
90	-22.6	-6.4	-4.2	-5.1	-1.9	-1.5	-.9	-1.2	.4
100	-17.5	-13.8	-3.2	-4.1	-4.3	-.9	-.5	-1.4	.6
110	-9.4	-20.7	-3.7	-2.1	-5.3	-1.4	.6	-1.8	.9
120	3.4	-26.6	-1.3	.3	-5.6	-1.8	1.3	-1.9	.6
130	18.6	-29.7	-.4	2.4	-5.7	-2.0	2.2	-1.9	.9
	35.0	-29.1	1.6	5.8	-5.3	-.1	3.1	-1.7	1.0
	48.2	-23.1	2.8	8.0	-3.9	-1.3	3.7	-1.2	1.8
160	55.5	-11.8	3.1	9.5	-1.9	.2	3.8	-.5	.1
170	53.6	3.3	3.0	10.5	.4	-1.3	3.7	-.1	1.3
180	40.4	18.5	1.8	9.1	2.8	-1.2	3.3	.5	-.3
190	19.0	29.3	.7	7.1	4.0	-1.3	2.5	.9	.1
200	-3.4	30.2	-1.7	4.2	4.5	-2.5	1.9	1.1	.6
210	-19.4	22.4	-5.2	1.6	3.6	-1.9	1.3	1.2	-.4
220	-22.5	7.7	-7.3	0.0	2.6	-1.6	.8	1.0	.7
230	-14.1	-5.5	-6.6	-.6	1.2	-2.0	.6	.8	.8
240	.2	-11.4	-3.7	-.8	.8	-1.2	.7	.7	.3
250	10.6	-7.8	-2.1	.7	1.0	-1.6	.3	.7	.7
260	12.0	2.1	-.7	.3	1.7	-2.2	.1	.9	.4
270	4.6	12.2	-2.0	-.6	2.4	-1.5	-.4	1.0	.9
280	-7.3	17.2	-.5	-1.8	2.7	-.9	-.9	1.0	.4
290	-18.6	16.8	-1.9	-2.8	2.7	-1.2	-1.2	.9	-.6
300	-26.6	11.9	-2.9	-4.6	2.2	-.9	-1.7	1.0	.6
310	-28.5	4.1	-3.9	-5.2	1.0	-.8	-1.9	.6	.3
320	-25.3	-3.5	-3.5	-6.1	-.4	-.2	-1.9	.4	.2
330	-19.2	-8.4	-3.7	-5.2	-.8	-1.3	-1.8	.1	1.3
340	-11.4	-9.9	-3.8	-4.0	-1.3	-1.2	-1.6	0.0	.8
350	-4.8	-9.5	-1.8	-3.6	-1.2	-.5	-1.5	0.0	.9

DIPOLE MOMENTS IN GAUSS-CM³

X	Y	Z	T
-11.0	2.7	2.2	11.5

FAST MUE END PLATE W/SHIELD END/2.1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION

DISTANCE (M)

POST 3G EXPOSURE

PROBE 1= .5 ; PROBE2= .75 ; PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	.8	-6.7	-1.7	-2.1	-.6	-.5	-1.2	-.4	-.4
10	2.6	-3.0	0.0	-2.2	0.0	.2	-1.1	-.3	-.9
20	2.2	.8	0.0	-1.7	-.2	.3	-1.2	-.4	-.3
30	-.7	4.2	.2	-1.9	.5	-.4	-1.3	-.3	.3
40	-5.2	6.8	.4	-2.6	1.0	-.7	-1.5	-.2	.3
50	-10.6	8.0	-2.3	-3.6	.7	-.8	-1.7	-.2	-.6
60	-16.3	7.5	-2.0	-4.2	.4	-.3	-1.8	-.4	-.3
70	-21.2	4.6	-2.3	-5.2	-.4	-1.1	-1.9	-.8	-1.1
80	-23.0	.3	-1.5	-5.0	-1.2	-.9	-1.7	-1.0	.1
90	-22.1	-6.0	-4.5	-4.9	-2.6	.7	-1.4	-1.3	-.2
100	-18.2	-13.0	-2.9	-4.1	-3.6	.1	-.9	-1.6	-.8
110	-9.6	-20.2	-2.7	-2.8	-5.1	-1.9	-.1	-2.0	.1
120	2.9	-26.3	-1.1	-.3	-5.7	.3	.8	-2.1	-.1
130	18.0	-29.6	1.5	2.3	-5.8	.7	1.6	-2.0	-.2
140	34.5	-28.2	2.1	5.4	-5.2	.9	2.3	-1.8	-.1
150	47.7	-22.3	2.8	7.8	-3.4	.6	2.9	-1.3	.6
160	54.9	-10.6	5.5	9.5	-1.5	-.3	3.2	-.7	.6
170	52.0	4.9	4.2	9.8	.9	-1.3	3.1	-.2	-.4
180	38.4	19.7	3.3	8.5	3.0	-1.2	2.8	.4	.6
190	16.1	29.5	1.0	6.9	4.3	-1.1	1.9	.7	.1
200	-6.3	30.5	-2.8	3.7	4.1	-.5	1.3	.9	-.4
210	-21.2	20.9	-3.0	1.3	3.6	-2.7	.8	.8	-1.4
220	-23.9	7.1	-6.6	-.6	2.1	-1.4	.4	.8	-1.0
230	-15.0	-6.5	-6.2	-1.0	1.2	-.6	.1	.7	.5
240	-.5	-11.9	-4.2	-.8	.3	.2	-.1	.5	-.5
250	9.7	-7.7	-.9	-.2	.9	-1.5	0.0	.4	-.1
260	11.5	2.1	-.3	.1	1.5	-1.8	-.2	.5	-.4
270	4.7	11.6	-.4	-.4	2.4	-.3	-.6	.6	-.1
280	-7.4	17.0	-.3	-1.5	2.5	-2.6	-1.0	.6	-.8
290	-19.0	16.1	-.9	-2.5	2.7	-.8	-1.5	.8	.8
300	-25.9	10.7	-2.2	-4.3	1.9	-.2	-1.6	.4	-.6
310	-27.0	3.3	-3.8	-5.0	.9	-1.0	-1.9	.1	-1.2
320	-24.2	-4.4	-3.8	-5.4	-.2	.4	-1.9	-.2	.2
330	-17.8	-8.2	-4.3	-4.6	-.8	-1.2	-1.6	-.3	.3
340	-10.2	-10.0	-1.3	-3.8	-1.2	-.5	-1.6	-.5	.4
350	-3.7	-9.5	-2.4	-3.3	-1.1	-.5	-1.5	-.5	.6

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
-10.2	2.7	1.4	10.7

FAST - PROC - 067

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE
Flight END Plate

Richard J Schnurr

Rick Schnurr 745.2

Timothy D Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

MUE Flight end plate

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure. Verify Rbs

Set up ESD station in Mag Cal Facility. Verify Rbs

Place printed wiring board on measurement stand. Verify Rbs

Measure Magnetic properties of Card. 1M 6.2 gauss Verify Rbs

Degauss Card. 30 gauss X into Y Verify Rbs

Measure Magnetic properties of Card. 1M 6.2 gauss Verify Rbs

Apply a ^{Three} gauss field to the card. Verify Rbs

Measure Magnetic properties of Card. 1M 6.0 gauss Verify Rbs

Degauss Card.

Measure Magnetic properties of Card. Verify Rbs

Repack Card in ESD container.

Verify Rbs

Removed
connector
squares
Rbs

Top of Box north
Card up

FAST MUE END PLATE

END/1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

NETIZATION
INITIAL PERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	35.9	10.3	3.5	10.3	4.4	1.0	4.1	2.1	.6
10	30.9	15.3	3.8	8.7	5.8	.6	3.2	2.5	-.1
20	24.2	20.7	2.0	7.6	6.7	0.0	2.4	3.0	.7
30	15.3	25.8	2.2	4.9	7.8	.1	1.4	3.1	.1
40	3.2	28.8	1.2	2.2	7.9	.4	-.1	3.3	.6
50	-8.5	30.3	.6	-1.0	8.0	.8	-1.2	3.3	-.2
60	-21.6	29.7	-1.6	-4.3	8.0	-.2	-2.6	3.2	.4
70	-32.7	27.3	-3.2	-7.4	7.1	-.3	-3.5	3.0	-.5
80	-41.9	23.0	-3.5	-9.9	6.7	-.2	-4.5	2.4	-.3
90	-48.2	15.9	-5.0	-12.1	4.5	.3	-5.3	1.8	.2
100	-51.2	8.4	-4.7	-14.0	2.6	-.7	-5.6	1.3	-.4
110	-48.6	.1	-5.4	-14.4	1.3	-.3	-5.5	.5	-.3
120	-42.9	-8.2	-4.4	-13.7	-.8	-.1	-5.7	-.2	-.3
130	-32.7	-14.0	-3.8	-12.7	-2.4	-.1	-5.1	-.7	-.6
140	-21.2	-16.9	-2.7	-10.8	-2.3	.7	-4.8	-.9	-.2
150	-11.3	-14.8	-1.6	-9.2	-1.9	0.0	-4.4	-.9	.2
160	-6.8	-8.5	-.2	-8.8	-2.0	.6	-3.9	-.8	-.4
170	-8.1	-.3	-.8	-7.6	-1.9	.3	-3.7	-1.2	-.1
180	-18.4	8.0	-1.8	-7.9	-1.4	-1.1	-3.5	-1.4	.1
190	-33.7	10.8	-2.4	-8.9	-1.9	-1.6	-3.1	-1.8	.3
200	-46.4	4.8	-5.7	-9.0	-3.7	-1.6	-2.8	-2.3	-.4
210	-50.0	-10.2	-6.6	-8.8	-5.7	-.5	-1.9	-2.9	-.6
220	-37.8	-28.6	-7.2	-7.1	-7.4	.2	-1.0	-3.3	.1
230	-13.7	-44.6	-4.7	-3.5	-9.4	-.2	.6	-3.8	-.5
240	16.4	-49.2	-1.6	.3	-9.8	-.3	2.0	-3.6	.6
250	39.9	-42.9	1.4	4.9	-8.7	1.5	3.3	-3.4	.2
260	52.7	-29.2	3.9	8.7	-6.8	.8	4.4	-2.8	.4
270	55.3	-13.9	6.1	11.8	-5.2	1.8	5.2	-2.2	.5
280	48.5	-2.9	5.6	12.1	-3.0	1.2	5.5	-1.5	.9
290	41.5	3.6	5.4	12.8	-1.4	2.0	5.8	-1.0	.6
300	34.9	4.3	3.3	13.0	-.7	2.1	5.9	-.4	1.0
310	32.0	2.8	5.2	12.4	.2	.1	6.2	-.1	-.3
320	31.9	.3	3.2	12.2	1.0	.8	5.9	.3	.8
330	34.1	-.2	1.6	11.9	1.3	1.3	5.6	.7	1.0
340	36.4	1.5	1.7	11.9	2.0	.2	5.3	1.2	1.1
350	36.8	5.5	1.0	11.0	4.0	.5	4.8	1.6	1.1

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
17.8	-20.0	.7	26.8

FAST MUE END PLATE

END/3 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERMDISTANCE (M)
PROBE 1= .5 ; PROBE 2= .75 ; PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	-	DATA	SCANS						
0	35.3	10.2	4.2	11.9	4.3	-.7	4.5	2.0	.6
10	30.4	15.2	2.9	9.8	5.4	-.3	3.6	2.5	.5
20	23.5	20.6	3.1	8.1	6.9	.1	2.5	2.9	.6
30	14.4	25.4	2.5	5.7	7.1	-.7	1.4	3.2	-.3
40	2.8	28.6	1.4	2.3	7.9	-1.2	.1	3.2	.4
50	-10.3	30.0	-.5	-1.1	8.0	-1.3	-1.7	3.2	-.2
60	-22.1	29.7	-1.6	-3.6	8.3	-.8	-2.8	3.3	-.3
70	-33.2	27.3	-3.0	-6.6	7.2	-.7	-4.1	3.0	-.2
80	-42.6	23.1	-3.5	-9.6	5.9	-1.9	-4.8	2.5	-.6
90	-48.7	15.7	-5.0	-11.6	4.8	-.8	-5.7	1.8	-.5
100	-51.3	7.7	-5.0	-12.9	2.4	-1.3	-6.0	1.3	.2
110	-49.3	-.3	-5.2	-13.1	1.6	-1.6	-6.2	.8	-.1
120	-42.9	-8.3	-4.5	-13.6	-.8	-1.7	-6.1	.1	-.6
130	-33.3	-14.4	-3.4	-12.2	-1.5	-1.4	-5.4	-.4	-.9
140	-21.8	-16.9	-4.0	-10.7	-3.1	-.3	-5.2	-.8	-.5
	-11.4	-15.8	-1.7	-8.9	-2.7	-1.0	-4.6	-1.1	-.5
	-5.9	-9.8	-1.1	-7.5	-2.6	-.7	-4.3	-1.2	.2
170	-7.2	-.5	-1.1	-7.1	-1.3	-.6	-4.0	-1.3	-.3
180	-17.0	7.2	-2.4	-7.1	-1.5	-1.4	-3.7	-1.4	-.2
190	-31.5	9.7	-3.5	-7.5	-1.7	-2.1	-3.4	-1.6	-.2
200	-43.8	4.3	-6.1	-8.1	-3.6	-2.4	-3.1	-1.9	.5
210	-47.4	-10.0	-6.6	-7.6	-5.3	-.7	-2.3	-2.5	-.7
220	-35.6	-28.2	-6.7	-5.6	-7.5	-1.2	-1.2	-3.0	-.4
230	-12.2	-42.8	-5.8	-2.6	-8.5	-1.2	.2	-3.4	.2
240	16.6	-47.6	-2.8	1.7	-9.4	.1	1.4	-3.5	-.2
250	39.8	-41.8	1.5	5.3	-8.4	-.4	2.9	-3.2	-.4
260	52.0	-27.5	2.7	9.4	-6.7	-.4	3.9	-2.6	.4
270	54.0	-12.8	5.0	11.5	-4.6	.6	4.8	-1.9	.9
280	47.8	-1.8	6.3	13.4	-3.0	.1	5.1	-1.2	.5
290	39.1	4.1	5.4	12.6	-1.1	-.8	5.4	-.7	1.0
300	32.5	5.1	3.8	12.8	-.2	-1.6	5.4	-.1	.1
310	29.7	2.6	4.7	12.2	.1	-.4	5.4	.1	-.4
320	30.2	.9	1.5	12.1	1.4	-.5	5.4	.4	.2
330	32.7	.7	2.6	12.2	1.9	-.9	4.9	.7	.7
340	34.8	1.6	3.0	11.6	2.2	-.8	4.7	1.1	.2
350	36.0	5.5	3.7	11.9	3.5	-.7	4.2	1.8	.3

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
17.0	-20.0	.5	26.2

FAST MUE END PLATE

END/2 DATE:12/13/93

NETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION

DISTANCE (M)

POST 3G EXPOSURE

PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	35.8	10.4	2.2	10.1	4.6	-.3	4.0	2.0	.8
10	31.9	14.7	2.5	9.0	5.1	1.3	3.3	2.4	-.6
20	24.5	20.1	1.8	7.9	6.1	.1	2.3	2.8	0.0
30	16.0	25.6	.8	6.1	7.3	.5	1.2	3.3	-.2
40	4.5	28.2	.5	2.8	7.7	.2	-.2	3.3	-.3
50	-8.4	30.1	-1.5	-.8	8.1	-.2	-1.3	3.2	-.2
60	-20.1	30.1	-2.0	-3.9	8.1	.7	-2.5	3.1	-.2
70	-31.8	27.7	-3.7	-6.3	7.4	.5	-3.6	2.9	-.3
80	-41.8	23.4	-5.2	-10.3	6.6	.2	-4.4	2.4	-.1
90	-49.8	16.0	-5.6	-12.3	4.8	-.3	-5.3	1.8	-.9
100	-52.8	8.2	-6.6	-12.7	2.5	-.7	-5.7	1.3	-.3
110	-52.8	.9	-7.0	-13.7	1.3	-.5	-5.7	.6	-.5
120	-43.7	-7.7	-7.2	-14.3	-.5	-.6	-5.6	0.0	-1.0
130	-32.9	-14.4	-4.2	-12.1	-2.3	.3	-5.4	-.3	-.8
140	-21.5	-17.3	-3.7	-10.4	-2.8	.1	-4.9	-1.0	-1.3
150	-11.2	-15.7	-2.8	-9.0	-2.7	.3	-4.5	-1.0	-1.0
160	-5.1	-9.5	-.9	-8.3	-2.3	-1.3	-4.0	-1.1	-.4
170	-8.4	-.6	-3.4	-7.7	-1.8	.2	-3.5	-1.3	-.8
180	-17.8	7.7	-4.0	-8.1	-1.5	-.3	-3.4	-1.3	-.8
190	-32.3	10.3	-5.6	-8.0	-2.1	-.6	-3.4	-1.6	.1
200	-44.9	4.6	-6.8	-8.9	-3.5	-.5	-2.7	-2.0	-.3
210	-47.2	-10.7	-8.3	-8.0	-5.6	1.5	-2.1	-2.5	-.6
220	-35.8	-28.6	-8.5	-6.3	-7.8	-.8	-1.1	-2.9	.4
230	-12.4	-43.7	-6.7	-3.4	-9.1	.4	.3	-3.4	-.2
240	16.2	-48.4	-2.7	2.0	-9.7	-1.4	1.7	-3.6	-.2
250	40.5	-41.7	-.4	5.4	-8.6	.1	3.3	-3.3	.2
260	52.4	-28.5	2.4	9.4	-6.5	.8	4.6	-2.7	-.8
270	54.0	-13.7	4.1	11.6	-4.7	-.8	5.1	-2.0	-.8
280	48.6	-3.0	4.8	12.8	-3.1	.3	5.5	-1.4	-.2
290	40.4	3.3	2.9	13.0	-1.4	2.5	5.6	-.8	.7
300	34.1	4.1	3.4	12.7	-.5	1.2	5.8	-.5	0.0
310	31.2	2.2	2.1	12.1	.2	1.1	5.6	0.0	0.0
320	32.3	.3	1.7	12.4	.6	1.6	5.6	.4	-.2
330	33.8	-.1	1.1	12.0	1.2	.6	5.4	.7	.1
340	35.9	1.5	2.3	11.9	1.9	.3	5.1	1.3	-.4
350	37.2	5.0	1.4	11.4	3.3	1.6	4.7	1.6	.7

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
17.6	-19.9	2.4	26.7

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE
Flight Power distribution

Richard Schnurr

Rick Schnurr 745.2

Tim Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

MUE Flight Power distribution

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure. Verify RTS

Set up ESD station in Mag Cal Facility. Verify RTS

Place printed wiring board on measurement stand. Verify RTS

Measure Magnetic properties of Card. 2 gauss / hour Verify RTS

Degauss Card. 30 g Verify RTS

Measure Magnetic properties of Card. 2 gauss / hour Verify RTS

Apply a ^{three} ~~one~~ gauss feild to the card. Field North Verify RTS

Measure Magnetic properties of Card. 0.2 gauss shift Verify RTS

Degauss Card. 30 g Verify RTS

Measure Magnetic properties of Card. Verify RTS

Repack Card in ESD container. Verify RTS

Remove connector
saves
RTS

Delete

Top of Box North
card up

FAST MUE PCU

PCU/3 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	3.1	.1	-2.5	2.0	.5	-1.2	1.4	.3	.1
10	3.7	.1	-2.9	2.6	.5	-1.3	1.2	.4	-1.1
20	4.1	.5	-2.4	2.4	.3	.2	1.1	.3	-.9
30	5.3	0.0	-1.9	2.1	.2	0.0	1.3	.3	.1
40	4.5	-.2	-2.4	2.2	.5	-.6	1.2	.6	-.1
50	5.1	0.0	-2.5	1.7	.3	-.4	1.1	.4	.5
60	4.7	.3	-1.3	1.7	.8	-1.1	1.0	.6	-.5
70	4.8	1.2	-.8	1.5	.6	-.7	.9	.6	-.9
80	4.3	1.7	-1.9	1.5	1.6	-.3	1.1	.6	-.9
90	4.7	2.4	-1.6	1.7	1.2	0.0	1.0	.6	-.6
100	3.9	4.0	-1.3	1.3	2.1	.2	.7	.8	-1.2
110	2.5	4.6	-1.7	.6	1.6	-1.6	.5	.9	-.8
120	.6	6.2	-2.1	.4	2.1	-1.0	-.2	1.1	-.2
130	-2.3	7.4	-3.2	-.8	2.1	-.9	-.5	1.0	.1
140	-5.8	9.1	-2.3	-1.4	2.3	-.5	-.8	1.0	-1.6
150	-10.1	10.5	-2.4	-2.3	2.5	-1.4	-1.2	1.2	-.9
160	-15.4	11.4	-4.1	-3.3	2.4	-.6	-1.4	1.1	-.7
170	-21.9	11.6	-4.2	-5.0	2.1	-.9	-1.9	.9	-1.1
180	-27.6	9.9	-6.2	-5.6	1.7	-1.2	-2.2	.7	-.4
190	-32.5	6.1	-7.3	-6.6	.5	-1.0	-2.2	.1	.1
200	-34.5	.2	-8.0	-7.0	-.7	-1.4	-2.0	-.1	-1.0
210	-32.0	-6.6	-7.5	-6.3	-2.0	-.9	-1.9	-.8	-1.2
220	-25.2	-13.9	-6.9	-5.8	-2.7	-.9	-1.8	-1.0	-.6
230	-14.9	-18.4	-6.3	-4.6	-3.4	-1.1	-1.3	-1.3	-.4
240	-3.3	-19.8	-7.3	-2.5	-3.8	-1.1	-.6	-1.4	-.6
250	5.9	-17.5	-5.9	-.8	-3.9	-1.7	-.1	-1.3	-1.0
260	12.1	-13.6	-4.8	.5	-2.7	-.6	.7	-1.1	-.6
270	15.0	-8.7	-3.0	2.2	-2.5	-.7	.8	-.8	.1
280	14.7	-3.9	-3.9	3.1	-1.4	-2.0	1.2	-.9	-1.0
290	13.2	-.8	-2.5	3.4	-1.3	-1.4	1.2	-.4	-.9
300	10.7	1.4	-2.8	3.4	-.6	-1.5	1.4	-.4	-.5
310	7.7	2.0	-2.8	3.2	-.3	-1.6	1.4	-.2	-.7
320	5.8	1.9	-4.0	2.8	.1	-1.4	1.4	-.1	-.6
330	4.6	1.8	-4.4	2.6	.2	-1.4	1.3	-.1	.3
340	3.6	1.6	-3.3	2.1	.4	.1	1.1	0.0	-.9
350	3.3	1.0	-2.4	2.0	.4	-1.5	1.1	0.0	-.5

DIPOLE MOMENTS IN GAUSS-CM³

X	Y	Z	T
8.8	-.0	4.5	9.9

FAST MUE PCU

PCU/2 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION

DISTANCE (M)

POST 3G EXPOSURE

PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	3.3	.1	-2.6	1.9	.3	-1.0	1.1	-.2	-.2
10	4.1	.2	-2.9	2.0	.1	-.8	.9	-.2	-.2
20	4.3	-.3	-2.6	2.2	.2	-1.0	1.0	-.1	-.3
30	4.5	.4	-2.5	1.9	.2	-1.4	.9	.1	-.4
40	5.1	-.5	-2.2	2.6	.2	-.7	.9	.1	.5
50	5.2	.1	-4.0	1.7	.5	-.4	.9	.1	-.4
60	5.0	.7	-.8	2.0	.6	-.5	.6	.1	-.7
70	4.6	1.1	-1.4	1.2	.6	-.7	.6	-.2	-.1
80	3.9	1.9	-1.8	1.1	.8	-1.2	.5	.1	-.8
90	3.7	2.8	-2.5	1.3	1.1	-.9	.3	.2	0.0
100	2.6	4.0	-1.3	1.1	1.5	-1.0	.1	.3	0.0
110	1.6	4.8	-1.3	.2	1.7	-1.8	-.1	.5	-.7
120	-.4	6.2	-2.8	.1	2.0	-1.3	-.5	.7	-1.1
130	-3.0	7.7	-2.7	-1.3	2.2	-1.7	-.8	.8	-.5
140	-7.0	9.2	-2.7	-1.6	2.4	-1.0	-1.0	.9	-.9
150	-11.4	10.5	-3.6	-3.1	2.4	.3	-1.5	.9	-.7
160	-16.9	11.0	-4.7	-3.9	2.5	.1	-2.0	.6	-.9
170	-23.1	11.5	-4.4	-5.6	2.2	-1.2	-2.3	.4	-.6
180	-29.4	9.8	-5.6	-6.2	1.4	-.9	-2.6	.1	-.6
190	-34.0	6.6	-7.6	-7.5	.8	-1.7	-2.8	-.2	-1.0
200	-35.7	.1	-7.4	-7.3	-.6	-1.5	-2.8	-.7	-.6
210	-33.6	-6.8	-7.6	-7.5	-2.2	-1.4	-2.4	-1.1	-1.2
220	-26.7	-14.2	-7.8	-6.7	-2.7	-2.0	-2.1	-1.3	-.9
230	-16.0	-18.6	-8.3	-5.1	-3.2	-.6	-1.6	-1.8	-1.6
240	-4.6	-20.4	-6.7	-2.9	-4.2	-1.3	-.9	-1.8	-1.5
250	5.2	-18.3	-6.6	-1.0	-4.0	-1.9	-.1	-1.7	0.0
260	11.5	-14.3	-4.4	.3	-3.5	-1.5	.4	-1.6	-.6
270	14.6	-9.5	-3.4	2.1	-2.7	-.8	.7	-1.4	-1.2
280	15.1	-4.9	-4.4	2.4	-1.8	-1.4	1.0	-1.2	-.7
290	13.5	-1.0	-3.7	3.2	-1.3	-.5	1.2	-1.0	-.4
300	10.6	.8	-2.7	3.3	-.4	-1.8	1.1	-.9	-.6
310	8.1	1.9	-2.6	3.1	-.3	-1.4	1.3	-.4	-.9
320	6.4	1.5	-3.1	3.2	-.3	-.7	1.2	-.3	-1.3
330	4.6	1.3	-4.7	2.9	.6	-1.6	1.2	-.1	-1.1
340	3.6	1.3	-4.4	2.4	.2	-2.0	1.1	-.1	-.9
350	3.6	.9	-4.1	2.2	.2	-1.9	1.0	-.1	-.5

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
9.4	-.1	4.9	10.6

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE
Flight Power distribution

Richard Schnurr

Rick Schnurr 745.2

Tim Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

MUE Flight Power distribution

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure.	Verify <u>RTS</u>
Set up ESD station in Mag Cal Facility.	Verify <u>RTS</u>
Place printed wiring board on measurement stand.	Verify <u>RTS</u> → Remove connector pins RTS
Measure Magnetic properties of Card.	Verify <u>RTS</u>
Degauss Card. 30 g	Verify <u>RTS</u>
Measure Magnetic properties of Card.	Verify <u>RTS</u>
Apply a ^{Three} gauss feild to the card.	Verify <u>RTS</u>
Measure Magnetic properties of Card.	Verify <u>RTS</u>
Degauss Card. 30 g	Verify <u>RTS</u>
Measure Magnetic properties of Card.	Verify <u>RTS</u> → Delete
Repack Card in ESD container.	Verify <u>RTS</u>

Top of Box North
Card up

FAST MUE PCU

PCU/3 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
FAST DEPERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	3.1	.1	-2.5	2.0	.5	-1.2	1.4	.3	.1
10	3.7	.1	-2.9	2.6	.5	-1.3	1.2	.4	-1.1
20	4.1	.5	-2.4	2.4	.3	.2	1.1	.3	-.9
30	5.3	0.0	-1.9	2.1	.2	0.0	1.3	.3	.1
40	4.5	-.2	-2.4	2.2	.5	-.6	1.2	.6	-.1
50	5.1	0.0	-2.5	1.7	.3	-.4	1.1	.4	.5
60	4.7	.3	-1.3	1.7	.8	-1.1	1.0	.6	-.5
70	4.8	1.2	-.8	1.5	.6	-.7	.9	.6	-.9
80	4.3	1.7	-1.9	1.5	1.6	-.3	1.1	.6	-.9
90	4.7	2.4	-1.6	1.7	1.2	0.0	1.0	.6	-.6
100	3.9	4.0	-1.3	1.3	2.1	.2	.7	.8	-1.2
110	2.5	4.6	-1.7	.6	1.6	-1.6	.5	.9	-.8
120	.6	6.2	-2.1	.4	2.1	-1.0	-.2	1.1	-.2
130	-2.3	7.4	-3.2	-.8	2.1	-.9	-.5	1.0	.1
140	-5.8	9.1	-2.3	-1.4	2.3	-.5	-.8	1.0	-1.6
150	-10.1	10.5	-2.4	-2.3	2.5	-1.4	-1.2	1.2	-.9
160	-15.4	11.4	-4.1	-3.3	2.4	-.6	-1.4	1.1	-.7
170	-21.9	11.6	-4.2	-5.0	2.1	-.9	-1.9	.9	-1.1
180	-27.6	9.9	-6.2	-5.6	1.7	-1.2	-2.2	.7	-.4
190	-32.5	6.1	-7.3	-6.6	.5	-1.0	-2.2	.1	.1
200	-34.5	.2	-8.0	-7.0	-.7	-1.4	-2.0	-.1	-1.0
210	-32.0	-6.6	-7.5	-6.3	-2.0	-.9	-1.9	-.8	-1.2
220	-25.2	-13.9	-6.9	-5.8	-2.7	-.9	-1.8	-1.0	-.6
230	-14.9	-18.4	-6.3	-4.6	-3.4	-1.1	-1.3	-1.3	-.4
240	-3.3	-19.8	-7.3	-2.5	-3.8	-1.1	-.6	-1.4	-.6
250	5.9	-17.5	-5.9	-.8	-3.9	-1.7	-.1	-1.3	-1.0
260	12.1	-13.6	-4.8	.5	-2.7	-.6	.7	-1.1	-.6
270	15.0	-8.7	-3.0	2.2	-2.5	-.7	.8	-.8	.1
280	14.7	-3.9	-3.9	3.1	-1.4	-2.0	1.2	-.9	-1.0
290	13.2	-.8	-2.5	3.4	-1.3	-1.4	1.2	-.4	-.9
300	10.7	1.4	-2.8	3.4	-.6	-1.5	1.4	-.4	-.5
310	7.7	2.0	-2.8	3.2	-.3	-1.6	1.4	-.2	-.7
320	5.8	1.9	-4.0	2.8	.1	-1.4	1.4	-.1	-.6
330	4.6	1.8	-4.4	2.6	.2	-1.4	1.3	-.1	.3
340	3.6	1.6	-3.3	2.1	.4	.1	1.1	0.0	-.9
350	3.3	1.0	-2.4	2.0	.4	-1.5	1.1	0.0	-.5

DIPOLE MOMENTS IN GAUSS-CM³

X	Y	Z	T
8.8	-.0	4.5	9.9

FAST MUE PCU

PCU/2 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION

DISTANCE (M)

POST 3G EXPOSURE

PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	3.3	.1	-2.6	1.9	.3	-1.0	1.1	-.2	-.2
10	4.1	.2	-2.9	2.0	.1	-.8	.9	-.2	-.2
20	4.3	-.3	-2.6	2.2	.2	-1.0	1.0	-.1	-.3
30	4.5	.4	-2.5	1.9	.2	-1.4	.9	.1	-.4
40	5.1	-.5	-2.2	2.6	.2	-.7	.9	.1	.5
50	5.2	.1	-4.0	1.7	.5	-.4	.9	.1	-.4
60	5.0	.7	-.8	2.0	.6	-.5	.6	.1	-.7
70	4.6	1.1	-1.4	1.2	.6	-.7	.6	-.2	-.1
80	3.9	1.9	-1.8	1.1	.8	-1.2	.5	.1	-.8
90	3.7	2.8	-2.5	1.3	1.1	-.9	.3	.2	0.0
100	2.6	4.0	-1.3	1.1	1.5	-1.0	.1	.3	0.0
110	1.6	4.8	-1.3	.2	1.7	-1.8	-.1	.5	-.7
120	-.4	6.2	-2.8	.1	2.0	-1.3	-.5	.7	-1.1
130	-3.0	7.7	-2.7	-1.3	2.2	-1.7	-.8	.8	-.5
140	-7.0	9.2	-2.7	-1.6	2.4	-1.0	-1.0	.9	-.9
150	-11.4	10.5	-3.6	-3.1	2.4	.3	-1.5	.9	-.7
160	-16.9	11.0	-4.7	-3.9	2.5	.1	-2.0	.6	-.9
170	-23.1	11.5	-4.4	-5.6	2.2	-1.2	-2.3	.4	-.6
180	-29.4	9.8	-5.6	-6.2	1.4	-.9	-2.6	.1	-.6
190	-34.0	6.6	-7.6	-7.5	.8	-1.7	-2.8	-.2	-1.0
200	-35.7	.1	-7.4	-7.3	-.6	-1.5	-2.8	-.7	-.6
210	-33.6	-6.8	-7.6	-7.5	-2.2	-1.4	-2.4	-1.1	-1.2
220	-26.7	-14.2	-7.8	-6.7	-2.7	-2.0	-2.1	-1.3	-.9
230	-16.0	-18.6	-8.3	-5.1	-3.2	-.6	-1.6	-1.8	-1.6
240	-4.6	-20.4	-6.7	-2.9	-4.2	-1.3	-.9	-1.8	-1.5
250	5.2	-18.3	-6.6	-1.0	-4.0	-1.9	-.1	-1.7	0.0
260	11.5	-14.3	-4.4	.3	-3.5	-1.5	.4	-1.6	-.6
270	14.6	-9.5	-3.4	2.1	-2.7	-.8	.7	-1.4	-1.2
280	15.1	-4.9	-4.4	2.4	-1.8	-1.4	1.0	-1.2	-.7
290	13.5	-1.0	-3.7	3.2	-1.3	-.5	1.2	-1.0	-.4
300	10.6	.8	-2.7	3.3	-.4	-1.8	1.1	-.9	-.6
310	8.1	1.9	-2.6	3.1	-.3	-1.4	1.3	-.4	-.9
320	6.4	1.5	-3.1	3.2	-.3	-.7	1.2	-.3	-1.3
330	4.6	1.3	-4.7	2.9	.6	-1.6	1.2	-.1	-1.1
340	3.6	1.3	-4.4	2.4	.2	-2.0	1.1	-.1	-.9
350	3.6	.9	-4.1	2.2	.2	-1.9	1.0	-.1	-.5

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
9.4	-.1	4.9	10.6

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE

EMP Plate

Richard J. Schnurr

Rick Schnurr 745.2

Timothy D. Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

MUE Flight end plate with shield

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure. Verify RLJ

Set up ESD station in Mag Cal Facility. Verify RLJ

Place printed wiring board on measurement stand. Verify

Measure Magnetic properties of Card. Verify

Degauss Card. Verify

Measure Magnetic properties of Card. ~~0000~~ Verify RLJ

Apply a ^{Three} ~~one~~ gauss feild to the card. Verify RLJ

Measure Magnetic properties of Card. Verify RLJ

Degauss Card. Verify RLJ

Measure Magnetic properties of Card. Verify

Repack Card in ESD container. Verify RLJ

already
done
Degaussed
Shield

Skip

FAST MUE END PLATE W/SHIELD END/3.1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERM

DISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	.4	-7.1	-1.1	-2.3	-.6	-.9	-.9	-.1	.7
10	2.3	-3.6	-.2	-1.7	-.4	-.3	-.8	-.2	-.1
20	1.6	-.1	-.8	-1.5	.2	-2.0	-.7	0.0	.1
30	-1.4	4.7	-.4	-2.2	.9	-1.6	-.8	0.0	.1
40	-5.7	6.4	-1.6	-2.6	.8	-1.7	-1.1	.1	.8
50	-10.7	7.6	-1.6	-3.3	1.2	-.9	-1.2	.2	.5
60	-16.4	7.0	-2.2	-4.1	.5	-2.3	-1.3	-.2	.3
70	-21.0	4.2	-3.2	-4.6	-.6	-1.3	-1.3	-.5	-.3
80	-23.2	-.1	-2.5	-5.2	-1.4	-2.5	-1.3	-.7	.4
90	-22.6	-6.4	-4.2	-5.1	-1.9	-1.5	-.9	-1.2	.4
100	-17.5	-13.8	-3.2	-4.1	-4.3	-.9	-.5	-1.4	.6
110	-9.4	-20.7	-3.7	-2.1	-5.3	-1.4	.6	-1.8	.9
120	3.4	-26.6	-1.3	.3	-5.6	-1.8	1.3	-1.9	.6
130	18.6	-29.7	-.4	2.4	-5.7	-2.0	2.2	-1.9	.9
140	35.0	-29.1	1.6	5.8	-5.3	-.1	3.1	-1.7	1.0
150	48.2	-23.1	2.8	8.0	-3.9	-1.3	3.7	-1.2	1.8
160	55.5	-11.8	3.1	9.5	-1.9	.2	3.8	-.5	.1
170	53.6	3.3	3.0	10.5	.4	-1.3	3.7	-.1	1.3
180	40.4	18.5	1.8	9.1	2.8	-1.2	3.3	.5	-.3
190	19.0	29.3	.7	7.1	4.0	-1.3	2.5	.9	.1
200	-3.4	30.2	-1.7	4.2	4.5	-2.5	1.9	1.1	.6
210	-19.4	22.4	-5.2	1.6	3.6	-1.9	1.3	1.2	-.4
220	-22.5	7.7	-7.3	0.0	2.6	-1.6	.8	1.0	.7
230	-14.1	-5.5	-6.6	-.6	1.2	-2.0	.6	.8	.8
240	.2	-11.4	-3.7	-.8	.8	-1.2	.7	.7	.3
250	10.6	-7.8	-2.1	.7	1.0	-1.6	.3	.7	.7
260	12.0	2.1	-.7	.3	1.7	-2.2	.1	.9	.4
270	4.6	12.2	-2.0	-.6	2.4	-1.5	-.4	1.0	.9
280	-7.3	17.2	-.5	-1.8	2.7	-.9	-.9	1.0	.4
290	-18.6	16.8	-1.9	-2.8	2.7	-1.2	-1.2	.9	-.6
300	-26.6	11.9	-2.9	-4.6	2.2	-.9	-1.7	1.0	.6
310	-28.5	4.1	-3.9	-5.2	1.0	-.8	-1.9	.6	.3
320	-25.3	-3.5	-3.5	-6.1	-.4	-.2	-1.9	.4	.2
330	-19.2	-8.4	-3.7	-5.2	-.8	-1.3	-1.8	.1	1.3
340	-11.4	-9.9	-3.8	-4.0	-1.3	-1.2	-1.6	0.0	.8
350	-4.8	-9.5	-1.8	-3.6	-1.2	-.5	-1.5	0.0	.9

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
-11.0	2.7	2.2	11.5

FAST MUE END PLATE W/SHIELD END/2.1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST 3G EXPOSURE

DISTANCE (M)
PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	- DATA SCANS								
0	.8	-6.7	-1.7	-2.1	-.6	-.5	-1.2	-.4	-.4
10	2.6	-3.0	0.0	-2.2	0.0	.2	-1.1	-.3	-.9
20	2.2	.8	0.0	-1.7	-.2	.3	-1.2	-.4	-.3
30	-.7	4.2	.2	-1.9	.5	-.4	-1.3	-.3	.3
40	-5.2	6.8	.4	-2.6	1.0	-.7	-1.5	-.2	.3
50	-10.6	8.0	-2.3	-3.6	.7	-.8	-1.7	-.2	-.6
60	-16.3	7.5	-2.0	-4.2	.4	-.3	-1.8	-.4	-.3
70	-21.2	4.6	-2.3	-5.2	-.4	-1.1	-1.9	-.8	-1.1
80	-23.0	.3	-1.5	-5.0	-1.2	-.9	-1.7	-1.0	.1
90	-22.1	-6.0	-4.5	-4.9	-2.6	.7	-1.4	-1.3	-.2
100	-18.2	-13.0	-2.9	-4.1	-3.6	.1	-.9	-1.6	-.8
110	-9.6	-20.2	-2.7	-2.8	-5.1	-1.9	-.1	-2.0	.1
120	2.9	-26.3	-1.1	-.3	-5.7	.3	.8	-2.1	-.1
130	18.0	-29.6	1.5	2.3	-5.8	.7	1.6	-2.0	-.2
140	34.5	-28.2	2.1	5.4	-5.2	.9	2.3	-1.8	-.1
150	47.7	-22.3	2.8	7.8	-3.4	.6	2.9	-1.3	.6
160	54.9	-10.6	5.5	9.5	-1.5	-.3	3.2	-.7	.6
170	52.0	4.9	4.2	9.8	.9	-1.3	3.1	-.2	-.4
180	38.4	19.7	3.3	8.5	3.0	-1.2	2.8	.4	.6
190	16.1	29.5	1.0	6.9	4.3	-1.1	1.9	.7	.1
200	-6.3	30.5	-2.8	3.7	4.1	-.5	1.3	.9	-.4
210	-21.2	20.9	-3.0	1.3	3.6	-2.7	.8	.8	-1.4
220	-23.9	7.1	-6.6	-.6	2.1	-1.4	.4	.8	-1.0
230	-15.0	-6.5	-6.2	-1.0	1.2	-.6	.1	.7	.5
240	-.5	-11.9	-4.2	-.8	.3	.2	-.1	.5	-.5
250	9.7	-7.7	-.9	-.2	.9	-1.5	0.0	.4	-.1
260	11.5	2.1	-.3	.1	1.5	-1.8	-.2	.5	-.4
270	4.7	11.6	-.4	-.4	2.4	-.3	-.6	.6	-.1
280	-7.4	17.0	-.3	-1.5	2.5	-2.6	-1.0	.6	-.8
290	-19.0	16.1	-.9	-2.5	2.7	-.8	-1.5	.8	.8
300	-25.9	10.7	-2.2	-4.3	1.9	-.2	-1.6	.4	-.6
310	-27.0	3.3	-3.8	-5.0	.9	-1.0	-1.9	.1	-1.2
320	-24.2	-4.4	-3.8	-5.4	-.2	.4	-1.9	-.2	.2
330	-17.8	-8.2	-4.3	-4.6	-.8	-1.2	-1.6	-.3	.3
340	-10.2	-10.0	-1.3	-3.8	-1.2	-.5	-1.6	-.5	.4
350	-3.7	-9.5	-2.4	-3.3	-1.1	-.5	-1.5	-.5	.6

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
-10.2	2.7	1.4	10.7

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE
Flight END Plate

Richard Schnurr

Rick Schnurr 745.2

Tim Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/13/93

Ron Kolecki 303.0

MUE Flight end plate

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure. Verify Rbs

Set up ESD station in Mag Cal Facility. Verify Rbs

Place printed wiring board on measurement stand. Verify Rbs

Measure Magnetic properties of Card. 1M 6.2 gauss Verify Rbs

Degauss Card. 30 gauss

X into Y
a little

Verify Rbs

Measure Magnetic properties of Card. 1M 6.2 gauss

Verify Rbs

Apply a ^{three} gauss field to the card. Verify Rbs

Measure Magnetic properties of Card. 1M 6.0 gauss

Verify Rbs

Degauss Card. Verify Rbs

Measure Magnetic properties of Card. Verify Verify

Repack Card in ESD container. Verify Rbs

Removed
connectors
saves
Rbs

Top of Box north
Card up.

FAST MUE END PLATE

END/1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
INITIAL PERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	35.9	10.3	3.5	10.3	4.4	1.0	4.1	2.1	.6
10	30.9	15.3	3.8	8.7	5.8	.6	3.2	2.5	-.1
20	24.2	20.7	2.0	7.6	6.7	0.0	2.4	3.0	.7
30	15.3	25.8	2.2	4.9	7.8	.1	1.4	3.1	.1
40	3.2	28.8	1.2	2.2	7.9	.4	-.1	3.3	.6
50	-8.5	30.3	.6	-1.0	8.0	.8	-1.2	3.3	-.2
60	-21.6	29.7	-1.6	-4.3	8.0	-.2	-2.6	3.2	.4
70	-32.7	27.3	-3.2	-7.4	7.1	-.3	-3.5	3.0	-.5
80	-41.9	23.0	-3.5	-9.9	6.7	-.2	-4.5	2.4	-.3
90	-48.2	15.9	-5.0	-12.1	4.5	.3	-5.3	1.8	.2
100	-51.2	8.4	-4.7	-14.0	2.6	-.7	-5.6	1.3	-.4
110	-48.6	.1	-5.4	-14.4	1.3	-.3	-5.5	.5	-.3
120	-42.9	-8.2	-4.4	-13.7	-.8	-.1	-5.7	-.2	-.3
130	-32.7	-14.0	-3.8	-12.7	-2.4	-.1	-5.1	-.7	-.6
140	-21.2	-16.9	-2.7	-10.8	-2.3	.7	-4.8	-.9	-.2
150	-11.3	-14.8	-1.6	-9.2	-1.9	0.0	-4.4	-.9	.2
160	-6.8	-8.5	-.2	-8.8	-2.0	.6	-3.9	-.8	-.4
170	-8.1	-.3	-.8	-7.6	-1.9	.3	-3.7	-1.2	-.1
180	-18.4	8.0	-1.8	-7.9	-1.4	-1.1	-3.5	-1.4	.1
190	-33.7	10.8	-2.4	-8.9	-1.9	-1.6	-3.1	-1.8	.3
200	-46.4	4.8	-5.7	-9.0	-3.7	-1.6	-2.8	-2.3	-.4
210	-50.0	-10.2	-6.6	-8.8	-5.7	-.5	-1.9	-2.9	-.6
220	-37.8	-28.6	-7.2	-7.1	-7.4	.2	-1.0	-3.3	.1
230	-13.7	-44.6	-4.7	-3.5	-9.4	-.2	.6	-3.8	-.5
240	16.4	-49.2	-1.6	.3	-9.8	-.3	2.0	-3.6	.6
250	39.9	-42.9	1.4	4.9	-8.7	1.5	3.3	-3.4	.2
260	52.7	-29.2	3.9	8.7	-6.8	.8	4.4	-2.8	.4
270	55.3	-13.9	6.1	11.8	-5.2	1.8	5.2	-2.2	.5
280	48.5	-2.9	5.6	12.1	-3.0	1.2	5.5	-1.5	.9
290	41.5	3.6	5.4	12.8	-1.4	2.0	5.8	-1.0	.6
300	34.9	4.3	3.3	13.0	-.7	2.1	5.9	-.4	1.0
310	32.0	2.8	5.2	12.4	.2	.1	6.2	-.1	-.3
320	31.9	.3	3.2	12.2	1.0	.8	5.9	.3	.8
330	34.1	-.2	1.6	11.9	1.3	1.3	5.6	.7	1.0
340	36.4	1.5	1.7	11.9	2.0	.2	5.3	1.2	1.1
350	36.8	5.5	1.0	11.0	4.0	.5	4.8	1.6	1.1

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
17.8	-20.0	.7	26.8

FAST MUE END PLATE

END/3 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	35.3	10.2	4.2	11.9	4.3	-.7	4.5	2.0	.6
10	30.4	15.2	2.9	9.8	5.4	-.3	3.6	2.5	.5
20	23.5	20.6	3.1	8.1	6.9	.1	2.5	2.9	.6
30	14.4	25.4	2.5	5.7	7.1	-.7	1.4	3.2	-.3
40	2.8	28.6	1.4	2.3	7.9	-1.2	.1	3.2	.4
50	-10.3	30.0	-.5	-1.1	8.0	-1.3	-1.7	3.2	-.2
60	-22.1	29.7	-1.6	-3.6	8.3	-.8	-2.8	3.3	-.3
70	-33.2	27.3	-3.0	-6.6	7.2	-.7	-4.1	3.0	-.2
80	-42.6	23.1	-3.5	-9.6	5.9	-1.9	-4.8	2.5	-.6
90	-48.7	15.7	-5.0	-11.6	4.8	-.8	-5.7	1.8	-.5
100	-51.3	7.7	-5.0	-12.9	2.4	-1.3	-6.0	1.3	.2
110	-49.3	-.3	-5.2	-13.1	1.6	-1.6	-6.2	.8	-.1
120	-42.9	-8.3	-4.5	-13.6	-.8	-1.7	-6.1	.1	-.6
130	-33.3	-14.4	-3.4	-12.2	-1.5	-1.4	-5.4	-.4	-.9
140	-21.8	-16.9	-4.0	-10.7	-3.1	-.3	-5.2	-.8	-.5
150	-11.4	-15.8	-1.7	-8.9	-2.7	-1.0	-4.6	-1.1	-.5
160	-5.9	-9.8	-1.1	-7.5	-2.6	-.7	-4.3	-1.2	.2
170	-7.2	-.5	-1.1	-7.1	-1.3	-.6	-4.0	-1.3	-.3
180	-17.0	7.2	-2.4	-7.1	-1.5	-1.4	-3.7	-1.4	-.2
190	-31.5	9.7	-3.5	-7.5	-1.7	-2.1	-3.4	-1.6	-.2
200	-43.8	4.3	-6.1	-8.1	-3.6	-2.4	-3.1	-1.9	.5
210	-47.4	-10.0	-6.6	-7.6	-5.3	-.7	-2.3	-2.5	-.7
220	-35.6	-28.2	-6.7	-5.6	-7.5	-1.2	-1.2	-3.0	-.4
230	-12.2	-42.8	-5.8	-2.6	-8.5	-1.2	.2	-3.4	.2
240	16.6	-47.6	-2.8	1.7	-9.4	.1	1.4	-3.5	-.2
250	39.8	-41.8	1.5	5.3	-8.4	-.4	2.9	-3.2	-.4
260	52.0	-27.5	2.7	9.4	-6.7	-.4	3.9	-2.6	.4
270	54.0	-12.8	5.0	11.5	-4.6	.6	4.8	-1.9	.9
280	47.8	-1.8	6.3	13.4	-3.0	.1	5.1	-1.2	.5
290	39.1	4.1	5.4	12.6	-1.1	-.8	5.4	-.7	1.0
300	32.5	5.1	3.8	12.8	-.2	-1.6	5.4	-.1	.1
310	29.7	2.6	4.7	12.2	.1	-.4	5.4	.1	-.4
320	30.2	.9	1.5	12.1	1.4	-.5	5.4	.4	.2
330	32.7	.7	2.6	12.2	1.9	-.9	4.9	.7	.7
340	34.8	1.6	3.0	11.6	2.2	-.8	4.7	1.1	.2
350	36.0	5.5	3.7	11.9	3.5	-.7	4.2	1.8	.3

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
17.0	-20.0	.5	26.2

FAST MUE END PLATE

END/2 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION

DISTANCE (M)

POST 3G EXPOSURE

PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	35.8	10.4	2.2	10.1	4.6	-.3	4.0	2.0	.8
10	31.9	14.7	2.5	9.0	5.1	1.3	3.3	2.4	-.6
20	24.5	20.1	1.8	7.9	6.1	.1	2.3	2.8	0.0
30	16.0	25.6	.8	6.1	7.3	.5	1.2	3.3	-.2
40	4.5	28.2	.5	2.8	7.7	.2	-.2	3.3	-.3
50	-8.4	30.1	-1.5	-.8	8.1	-.2	-1.3	3.2	-.2
60	-20.1	30.1	-2.0	-3.9	8.1	.7	-2.5	3.1	-.2
70	-31.8	27.7	-3.7	-6.3	7.4	.5	-3.6	2.9	-.3
80	-41.8	23.4	-5.2	-10.3	6.6	.2	-4.4	2.4	-.1
90	-49.1	16.0	-5.6	-12.3	4.8	-.3	-5.3	1.8	-.9
100	-50.0	8.2	-6.6	-12.7	2.5	-.7	-5.7	1.3	-.3
110	-49.2	.9	-7.0	-13.7	1.3	-.5	-5.7	.6	-.5
120	-43.7	-7.7	-7.2	-14.3	-.5	-.6	-5.6	0.0	-1.0
130	-32.9	-14.4	-4.2	-12.1	-2.3	.3	-5.4	-.3	-.8
140	-21.5	-17.3	-3.7	-10.4	-2.8	.1	-4.9	-1.0	-1.3
150	-11.2	-15.7	-2.8	-9.0	-2.7	.3	-4.5	-1.0	-1.0
160	-5.1	-9.5	-.9	-8.3	-2.3	-1.3	-4.0	-1.1	-.4
170	-8.4	-.6	-3.4	-7.7	-1.8	.2	-3.5	-1.3	-.8
180	-17.8	7.7	-4.0	-8.1	-1.5	-.3	-3.4	-1.3	-.8
190	-32.3	10.3	-5.6	-8.0	-2.1	-.6	-3.4	-1.6	.1
200	-44.9	4.6	-6.8	-8.9	-3.5	-.5	-2.7	-2.0	-.3
210	-47.2	-10.7	-8.3	-8.0	-5.6	1.5	-2.1	-2.5	-.6
220	-35.8	-28.6	-8.5	-6.3	-7.8	-.8	-1.1	-2.9	.4
230	-12.4	-43.7	-6.7	-3.4	-9.1	.4	.3	-3.4	-.2
240	16.2	-48.4	-2.7	2.0	-9.7	-1.4	1.7	-3.6	-.2
250	40.5	-41.7	-.4	5.4	-8.6	.1	3.3	-3.3	.2
260	52.4	-28.5	2.4	9.4	-6.5	.8	4.6	-2.7	-.8
270	54.0	-13.7	4.1	11.6	-4.7	-.8	5.1	-2.0	-.8
280	48.6	-3.0	4.8	12.8	-3.1	.3	5.5	-1.4	-.2
290	40.4	3.3	2.9	13.0	-1.4	2.5	5.6	-.8	.7
300	34.1	4.1	3.4	12.7	-.5	1.2	5.8	-.5	0.0
310	31.2	2.2	2.1	12.1	.2	1.1	5.6	0.0	0.0
320	32.3	.3	1.7	12.4	.6	1.6	5.6	.4	-.2
330	33.8	-.1	1.1	12.0	1.2	.6	5.4	.7	.1
340	35.9	1.5	2.3	11.9	1.9	.3	5.1	1.3	-.4
350	37.2	5.0	1.4	11.4	3.3	1.6	4.7	1.6	.7

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
17.6	-19.9	2.4	26.7

FAST - PROC - 067

SMEX FAST MUE BOARD
MAGNETICS PROCEDURE

Flrst BCC

Richard D Schnurr

Rick Schnurr 745.2

Timothy D Gruner

Tim Gruner 745.2

Dave Everett 12/13/93

Dave Everett 743.1

Ron Kolecki 12/3/93

Ron Kolecki 303.0

MUE Flash BCC Battery charge control

This procedure is intended to characterize and initialize the magnetic properties of a FAST MUE electronics board assembly.

Call Quality Assurance before starting procedure.	Verify <u>R65</u>	
Set up ESD station in Mag Cal Facility.	Verify <u>R65</u>	
Place printed wiring board on measurement stand.	Verify <u>R65</u>	→ Remove connector. R65
Measure Magnetic properties of Card.	Verify <u>R65</u>	
Degauss Card. 30 gauss	Verify <u>R65</u>	
Measure Magnetic properties of Card.	Verify <u>R65</u>	
Apply a ^{Three} gauss field to the card. in X direction	Verify <u>R65</u>	
Measure Magnetic properties of Card.	Verify <u>R65</u>	
Degauss Card. 30 gauss	Verify <u>R65</u>	
Measure Magnetic properties of Card.	Verify <u>_____</u>	skipped
Repack Card in ESD container.	Verify <u>R65</u>	

Top of Box North (X)
card up

FAST MUE BCC

BCC/1 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
INITIAL PERMDISTANCE (M)
PROBE 1= 1 ; PROBE 2= 1.25 ; PROBE 3= 1.5

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	-.3	-.5	-.2	-.3	-.3	-.0	.1	-.3	.2
10	0.0	-.5	-.3	.1	.1	.1	-.1	-.4	.2
20	-.5	-.1	-.4	-.4	-.5	-.0	-.1	-.3	.1
30	-.3	-.3	-.4	.2	-.2	.1	-.1	-.3	.2
40	-.2	-.6	-.3	-.3	-.3	.1	-.1	0.0	.2
50	-.4	.1	-.3	.1	-.4	-.1	-.1	0.0	.1
60	0.0	-.5	-.3	.4	-.2	.0	-.1	-.1	.2
70	-.6	-.3	-.1	.1	-.4	.3	-.3	-.2	.2
80	.1	.1	-.3	.3	.1	.1	-.1	-.2	.1
90	-.2	-.3	-.4	.1	-.1	.0	-.1	-.2	.1
100	-.4	-.5	-.3	-.1	-.3	-.0	-.1	-.2	.1
110	-.2	-.5	-.4	.2	-.3	-.0	-.2	-.1	.1
120	-.2	-.6	-.4	-.1	-.4	.0	-.2	-.1	.1
130	-.2	-.4	-.4	.2	-.3	.0	-.2	-.2	.1
140	.1	-.5	-.3	-.2	-.3	.0	-.1	-.2	.1
150	0.0	-.4	-.4	.5	-.2	-.0	-.1	-.2	.1
160	-.1	-.4	-.3	.2	-.4	.0	.1	-.3	.1
170	-.1	-.4	-.3	.4	-.3	.1	-.1	-.2	.2
180	0.0	-.3	-.4	.3	-.2	-.1	-.2	0.0	.1
190	-.2	-.5	-.3	.5	-.4	-.1	-.1	-.1	.1
200	.1	-.6	-.5	.4	-.5	-.1	-.1	-.1	.1
210	.2	-.5	-.4	.6	-.4	.1	.1	-.1	.1
220	0.0	.2	-.3	.4	.3	.1	.1	-.2	.1
230	.1	-.4	-.3	.5	-.3	.0	.1	-.2	.2
240	-.2	-.2	-.3	-.1	-.4	.0	.1	-.1	.1
250	-.3	-.4	-.3	-.1	-.3	-.0	-.2	0.0	.1
260	-.5	-.4	-.2	-.3	-.3	.0	-.1	-.2	.2
270	-.2	-.4	-.4	.1	-.2	.1	-.3	-.1	.2
280	-.5	-.2	-.3	.1	-.2	-.0	.1	-.1	.3
290	-.4	-.1	-.2	.1	-.2	.0	-.1	-.2	-.1
300	-.4	-.1	-.1	-.1	.2	.1	-.2	-.2	.2
310	-.3	-.3	-.2	.1	-.2	-.1	-.1	-.1	.1
320	.1	-.8	-.4	.4	.1	.0	-.2	-.2	.2
330	0.0	.1	-.2	-.1	-.5	-.1	-.1	-.1	-.0
340	-.3	-.3	-.1	-.2	-.4	.1	.1	-.3	.2
350	.2	-.4	-.2	.4	-.5	.0	-.1	-.1	.1

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
-.5	-.0	99.5	99.5

FAST MUE BCC

BCC/3 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
POST DEPERMDISTANCE (M)
PROBE 1= .5 : PROBE 2= .75 : PROBE 3= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	DATA SCANS								
0	.6	.1	-5.2	-.8	.1	-.9	-.7	.1	.0
10	-.2	.2	-5.0	-.5	.3	-.2	-.3	.1	-.2
20	.3	-.3	-5.4	-.6	-.4	-.9	-.6	.1	-.2
30	-.3	-.1	-5.3	-.6	.7	-1.4	-.8	0.0	-.1
40	-.4	-.2	-5.6	-.2	.2	-.7	-.4	-.1	.0
50	-.7	.2	-5.5	-.8	-.2	-.8	-.6	-.1	-.3
60	.6	.3	-5.9	-.2	-.4	-1.4	-.6	.1	-.3
70	.2	0.0	-5.6	.2	.1	-.8	-.6	.1	-.1
80	.3	-.4	-7.5	-.6	.1	-1.0	-.6	0.0	-.2
90	.1	-.2	-7.1	-.7	0.0	-1.2	-.7	-.1	-.1
100	.6	0.0	-7.3	-.3	-.6	-1.0	-.9	-.3	-.1
110	-.6	.1	-7.0	-.9	-.1	-.4	-.7	-.1	-.3
120	-.2	-.2	-8.0	-.7	-.4	-1.0	-.8	0.0	-.0
130	-.2	-.1	-5.6	-.2	-.5	-.8	-.6	-.2	.0
140	-1.2	-.4	-7.7	-.9	.3	-1.1	-.6	-.2	-.2
150	-.9	-.1	-7.1	-.7	.2	-1.6	-.6	-.1	-.3
160	-.4	-1.0	-5.9	.1	-.2	-.5	-.6	0.0	-.4
170	-.3	-.6	-6.0	-.4	-.3	-.5	-.7	.1	-.2
180	.6	-.9	-5.1	-.3	-.3	-.4	-.6	-.2	-.2
190	.7	-.7	-5.8	-.3	-.3	-.1	-.6	0.0	-.4
200	1.0	-.9	-4.4	-.2	-.2	-.8	-.6	-.2	-.0
210	-.1	-.6	-4.0	-1.1	0.0	-1.2	-.3	-.2	-.3
220	.9	-1.3	-4.0	-.3	-.3	-.4	-.4	-.3	-.2
230	1.7	-.5	-3.3	.5	-.4	-.4	-.6	-.1	-.2
240	.4	-.1	-3.7	-.4	.2	-.3	-.3	-.4	-.0
250	1.7	-.4	-3.3	.3	-.5	-.2	-.5	-.2	-.1
260	1.2	-.3	-3.9	.4	.1	-.1	-.7	-.5	-.2
270	1.4	-.1	-3.1	.1	-.4	-.1	-.5	-.4	-.2
280	.3	1.1	-3.6	-.9	.2	-.4	-.5	-.3	-.1
290	1.1	-.5	-3.8	.3	-.4	-.1	-.6	-.4	-.2
300	1.7	.4	-1.9	.5	-.4	-.5	-.5	-.1	-.2
310	.9	0.0	-2.4	.6	-.3	-.7	-.6	-.2	-.2
320	-.1	0.0	-3.5	-.3	.5	-1.3	-.7	0.0	-.1
330	-.3	-.1	-4.5	-.2	.4	-1.2	-.5	-.1	-.3
340	-.6	.5	-4.7	-1.5	.1	-.9	-.5	-.1	-.1
350	.2	-.1	-3.2	-.3	-.4	-.8	-.7	.1	-.2

DIPOLE MOMENTS IN GAUSS-CM³

X	Y	Z	T
-.0	-.4	6.2	6.2

FAST MUE BCC

BCC/2 DATE:12/13/93

MAGNETIZATION

PROBE DISTANCE IN METERS

MAGNETIZATION
PUST 3G EXPOSUREDISTANCE (M)
PROBE 1= .5 : PROBE2= .75 : PROBE 2= 1

MAGNETIC FIELD IN NANOTESLA

BKGS	X1	Y1	Z1	X2	Y2	Z2	X3	Y3	Z3
ANGLE	-	DATA	SCANS						
0	1.4	-.3	-5.5	-.4	-.1	-.7	.5	-.3	-.3
10	.7	.4	-5.6	.4	-.3	-.3	.3	-.2	-.2
20	1.1	.3	-4.6	0.0	.1	-.7	.3	-.2	-.4
30	.5	.2	-4.3	-.1	.1	-.3	.2	-.3	-.3
40	.5	.4	-5.6	-.3	-.2	-1.6	.3	-.2	-.2
50	.9	.3	-5.8	-.6	0.0	-1.1	.2	-.1	-.1
60	.9	0.0	-6.1	1.1	0.0	-.7	.5	-.1	-.0
70	1.1	.4	-7.0	0.0	-.2	-.9	-.1	0.0	-.2
80	.6	-.1	-7.6	-.4	.2	-.6	.1	-.1	-.3
90	1.1	-.3	-7.9	1.3	-.1	-.5	.4	.2	-.2
100	1.4	.4	-8.8	.3	-.2	-.8	.2	.2	-.2
110	-.4	.2	-8.4	-.1	.2	-.3	.3	.1	-.1
120	-.8	.3	-9.1	-.8	.4	-.6	.5	-.2	-.3
130	.4	-.7	-8.0	.8	-.6	-1.1	.3	-.1	-.1
140	.7	-.4	-7.4	-.1	-.2	-.6	-.5	-.1	-.1
150	-.5	.1	-7.1	-.9	-.5	-.4	.2	-.1	-.1
160	-.9	-1.0	-6.9	-.6	-.3	-.6	-.3	-.1	-.2
170	-.2	-1.0	-6.6	-.9	-.7	-.9	-.6	0.0	-.2
180	-.5	-.9	-6.8	-1.4	-.1	-.3	-.6	-.2	-.0
190	.9	-.7	-6.6	-.2	-.4	-.4	-.3	-.2	-.1
200	.5	-.7	-4.6	-.5	-.5	-.2	-.2	-.3	-.0
210	.5	-.9	-5.9	-.5	-.5	-.5	-.3	-.2	-.2
220	1.1	-.8	-4.5	-.6	-.4	-.1	-.3	-.3	-.1
230	.6	-.7	-4.8	.1	-.5	-.9	-.3	.1	-.1
240	1.2	-.7	-4.6	-.5	-.6	-.3	-.4	-.1	-.1
250	.8	-.5	-4.8	.2	-.6	-.2	-.4	-.1	-.2
260	1.3	-.9	-3.7	-.2	-.2	-.4	-.5	0.0	0.0
270	.5	-.2	-4.3	-.3	-.3	-.2	-.2	.1	-.1
280	0.0	-.3	-4.0	-.5	-.1	-.6	-.2	0.0	-.0
290	.8	-.6	-4.6	-.6	-.9	.1	-.1	0.0	-.2
300	1.0	-.7	-3.8	.3	-.5	-.2	-.3	0.0	-.1
310	1.4	-.7	-3.8	.3	-.9	-.1	-.2	-.1	-.2
320	.5	0.0	-4.1	-.9	-.2	-.7	-.3	-.1	-.1
330	-.4	-.4	-5.0	-.9	.4	-1.2	-.4	-.2	-.1
340	.5	.3	-4.5	-.8	-.3	-.5	-.2	0.0	-.2
350	.6	.6	-5.4	-.2	.4	-.6	-.4	0.0	-.1

DIPOLE MOMENTS IN GAUSS-CM^3

X	Y	Z	T
.2	-.1	7.4	7.4